

FEATURES

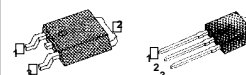
- ◆ Avalanche Rugged Technology
- ◆ Rugged Gate Oxide Technology
- ◆ Lower Input Capacitance
- ◆ Improved Gate Charge
- ◆ Extended Safe Operating Area
- ◆ Lower Leakage Current: 10 μ A (Max.) @ $V_{DS} = 200V$
- ◆ Lower $R_{DS(ON)}$: 1.185 Ω (Typ.)

$$BV_{DSS} = 200 \text{ V}$$

$$R_{DS(on)} = 1.5\Omega$$

$$I_D = 2.7 \text{ A}$$

D-PAK **I-PAK**



1. Gate 2. Drain 3. Source

Absolute Maximum Ratings

Symbol	Characteristic	Value	Units
V_{DSS}	Drain-to-Source Voltage	200	V
I_D	Continuous Drain Current ($T_C=25^\circ\text{C}$)	2.7	A
	Continuous Drain Current ($T_C=100^\circ\text{C}$)	1.7	
I_{DM}	Drain Current-Pulsed (1)	9	A
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS}	Single Pulsed Avalanche Energy (2)	24	mJ
I_{AR}	Avalanche Current (1)	2.7	A
E_{AR}	Repetitive Avalanche Energy (1)	2.1	mJ
dv/dt	Peak Diode Recovery dv/dt (3)	5	V/ns
P_D	Total Power Dissipation ($T_A=25^\circ\text{C}$) *	2.5	W
	Total Power Dissipation ($T_C=25^\circ\text{C}$)	21	W
	Linear Derating Factor	0.17	W/ $^\circ\text{C}$
T_J, T_{STG}	Operating Junction and Storage Temperature Range	- 55 to +150	$^\circ\text{C}$
T_L	Maximum Lead Temp. for Soldering Purposes, 1/8. from case for 5-seconds	300	

Thermal Resistance

Symbol	Characteristic	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	--	5.7	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Junction-to-Ambient *	--	50	
$R_{\theta JA}$	Junction-to-Ambient	--	110	

* When mounted on the minimum pad size recommended (PCB Mount).

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Rev. B

Electrical Characteristics ($T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
BV_{DSS}	Drain-Source Breakdown Voltage	200	--	--	V	$V_{GS}=0V, I_D=250\mu\text{A}$
$\Delta BV/\Delta T_J$	Breakdown Voltage Temp. Coeff.	--	0.19	--	V/ $^\circ\text{C}$	$I_D=250\mu\text{A}$ See Fig 7
$V_{GS(th)}$	Gate Threshold Voltage	1.0	--	2.0	V	$V_{DS}=5V, I_D=250\mu\text{A}$
I_{GSS}	Gate-Source Leakage, Forward	--	--	100	nA	$V_{GS}=20V$
	Gate-Source Leakage, Reverse	--	--	-100		$V_{GS}=-20V$
I_{DSS}	Drain-to-Source Leakage Current	--	--	10	μA	$V_{DS}=200V$
		--	--	100		$V_{DS}=160V, T_C=125^\circ\text{C}$
$R_{DS(on)}$	Static Drain-Source On-State Resistance	--	--	1.5	Ω	$V_{GS}=5V, I_D=1.35A$ (4)
g_{fs}	Forward Transconductance	--	1.9	--	$\bar{\Omega}$	$V_{DS}=40V, I_D=1.35A$ (4)
C_{iss}	Input Capacitance	--	185	240	pF	$V_{GS}=0V, V_{DS}=25V, f=1\text{MHz}$ See Fig 5
C_{oss}	Output Capacitance	--	35	45		
C_{rss}	Reverse Transfer Capacitance	--	14	20		
$t_{d(on)}$	Turn-On Delay Time	--	9	30	ns	$V_{DD}=100V, I_D=3.3A,$ $R_G=22\Omega$ See Fig 13 (4) (5)
t_r	Rise Time	--	9	30		
$t_{d(off)}$	Turn-Off Delay Time	--	20	50		
t_f	Fall Time	--	6	20		
Q_g	Total Gate Charge	--	6.1	9	nC	$V_{DS}=160V, V_{GS}=5V,$ $I_D=3.3A$ See Fig 6 & Fig 12 (4) (5)
Q_{gs}	Gate-Source Charge	--	1.4	--		
Q_{gd}	Gate-Drain (. Miller.) Charge	--	2.8	--		

Source-Drain Diode Ratings and Characteristics

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Condition
I_S	Continuous Source Current	--	--	2.7	A	Integral reverse pn-diode in the MOSFET
I_{SM}	Pulsed-Source Current (1)	--	--	9		
V_{SD}	Diode Forward Voltage (4)	--	--	1.5	V	$T_J=25^\circ\text{C}, I_S=2.7A, V_{GS}=0V$
t_{rr}	Reverse Recovery Time	--	123	--	ns	$T_J=25^\circ\text{C}, I_F=3.3A$
Q_{rr}	Reverse Recovery Charge	--	0.38	--	μC	$di_F/dt=100A/\mu\text{s}$ (4)

Notes;

- Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
- $L=5\text{mH}, I_{AS}=2.7A, V_{DD}=50V, R_G=27\Omega,$ Starting $T_J=25^\circ\text{C}$
- $I_{SD} \leq 3.3A, di/dt \leq 140A/\mu\text{s}, V_{DD} \leq BV_{DSS},$ Starting $T_J=25^\circ\text{C}$
- Pulse Test: Pulse Width = $250\mu\text{s},$ Duty Cycle $\leq 2\%$
- Essentially Independent of Operating Temperature

Fig 1. Output Characteristics

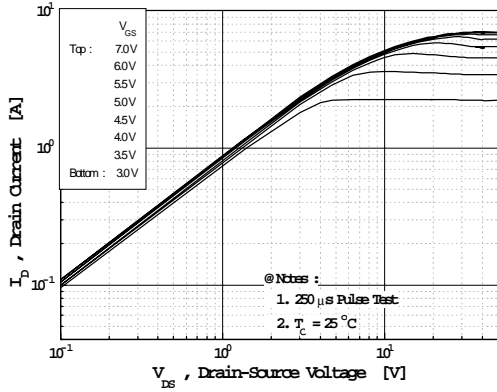


Fig 2. Transfer Characteristics

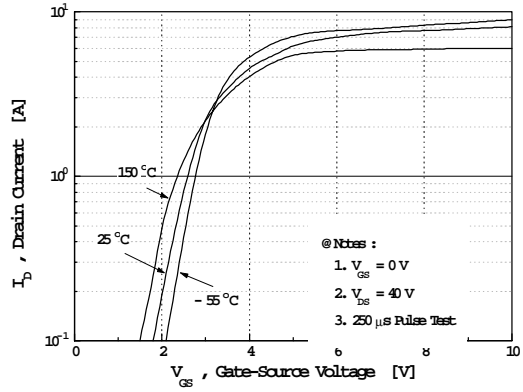


Fig 3. On-Resistance vs. Drain Current

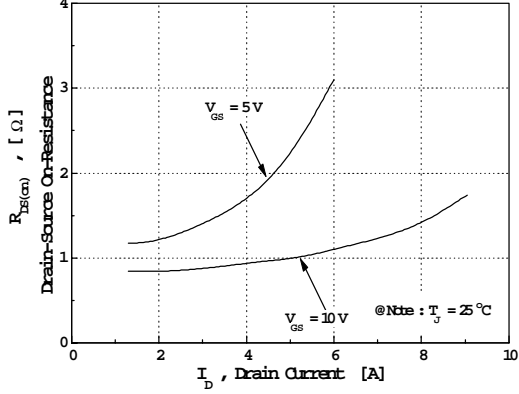


Fig 4. Source-Drain Diode Forward Voltage

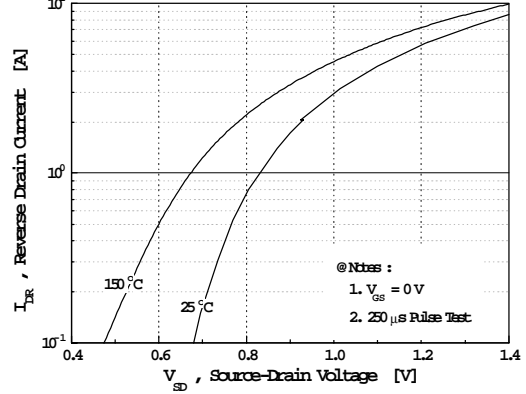


Fig 5. Capacitance vs. Drain-Source Voltage

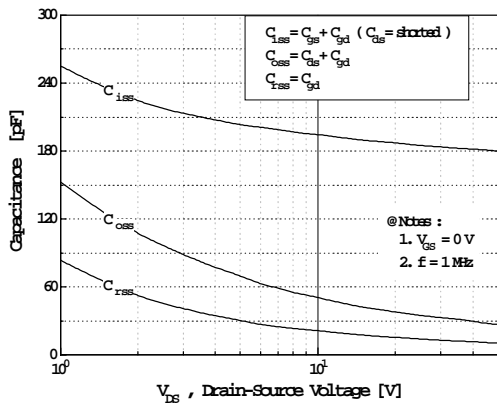


Fig 6. Gate Charge vs. Gate-Source Voltage

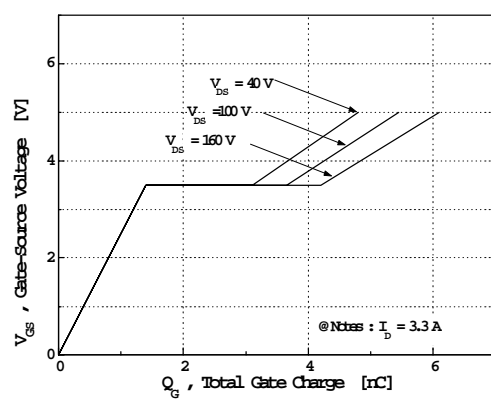


Fig 7. Breakdown Voltage vs. Temperature

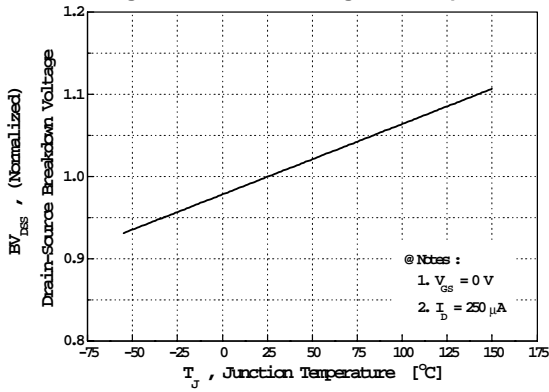


Fig 8. On-Resistance vs. Temperature

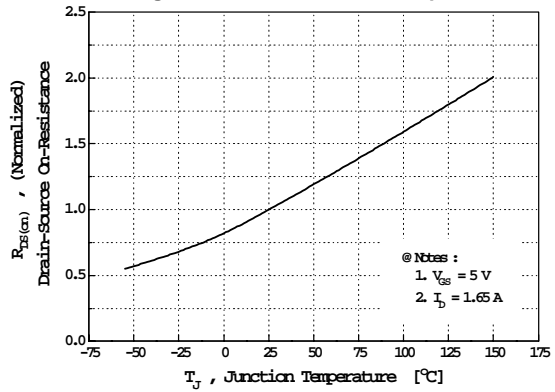


Fig 9. Max. Safe Operating Area

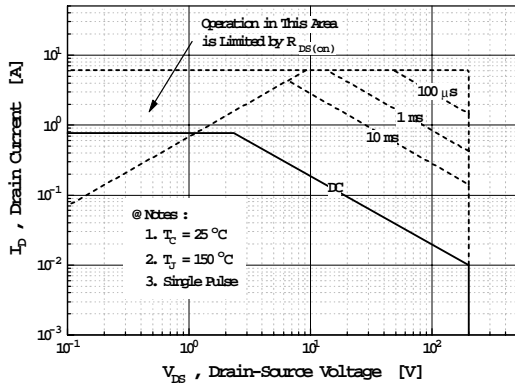


Fig 10. Max. Drain Current vs. Ambient Temperature

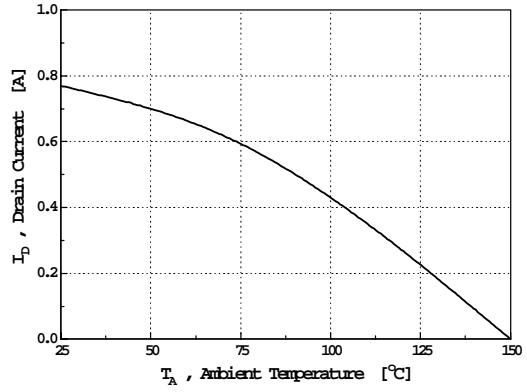


Fig 11. Thermal Response

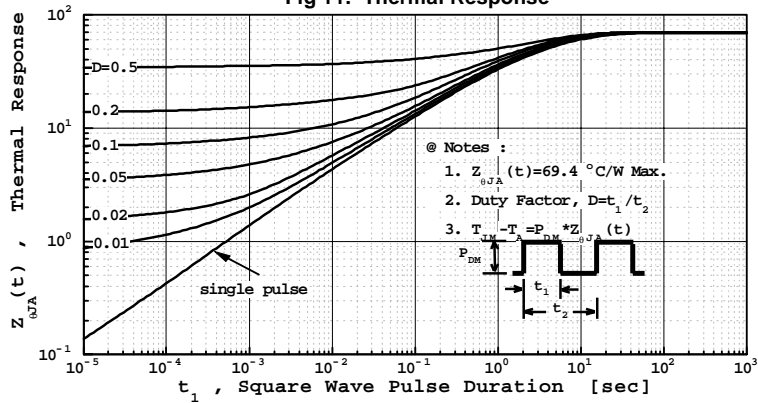


Fig 12. Gate Charge Test Circuit & Waveform

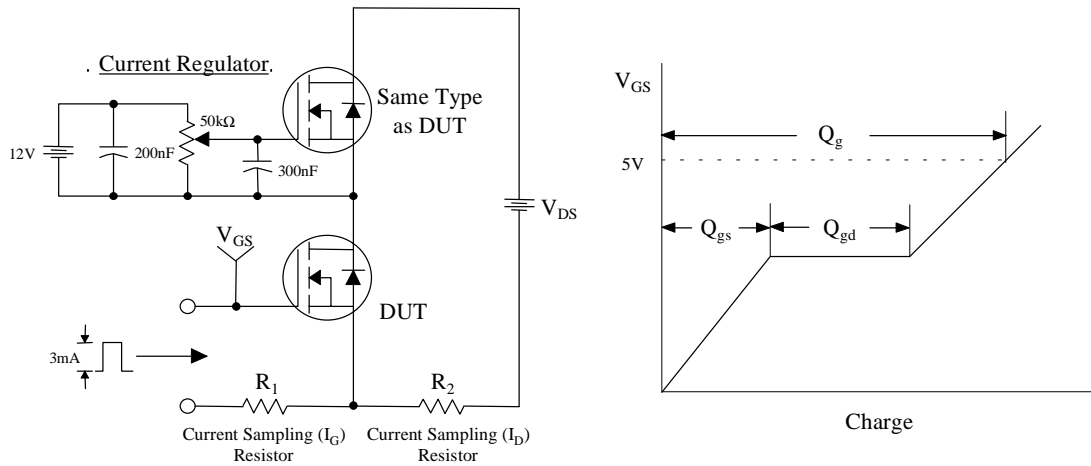


Fig 13. Resistive Switching Test Circuit & Waveforms

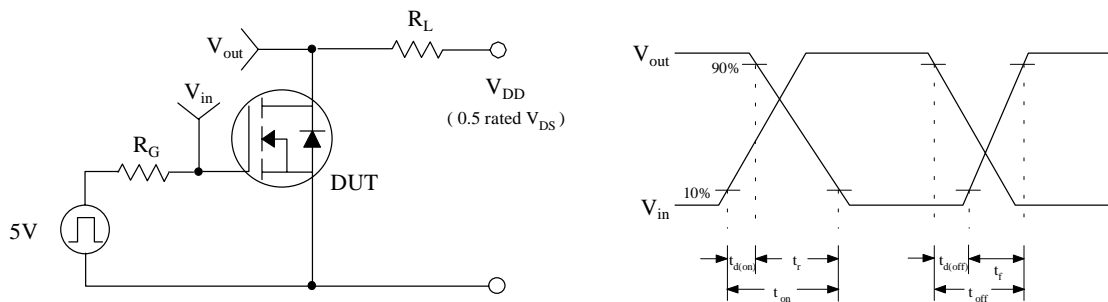


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms

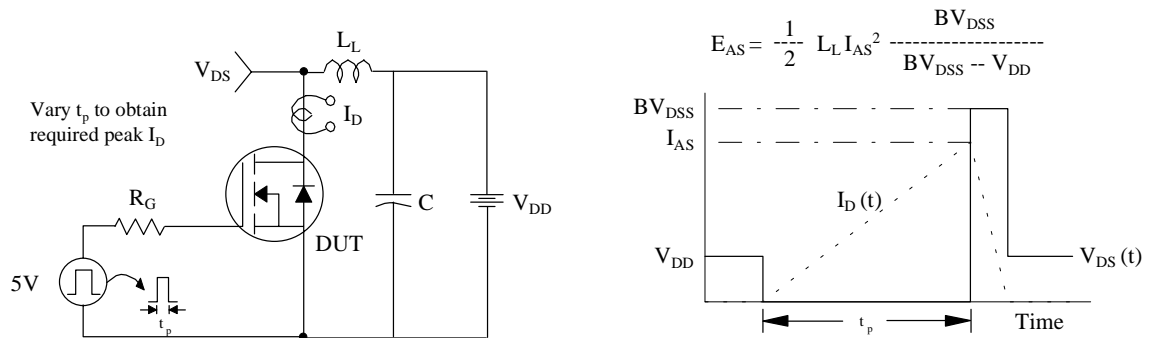
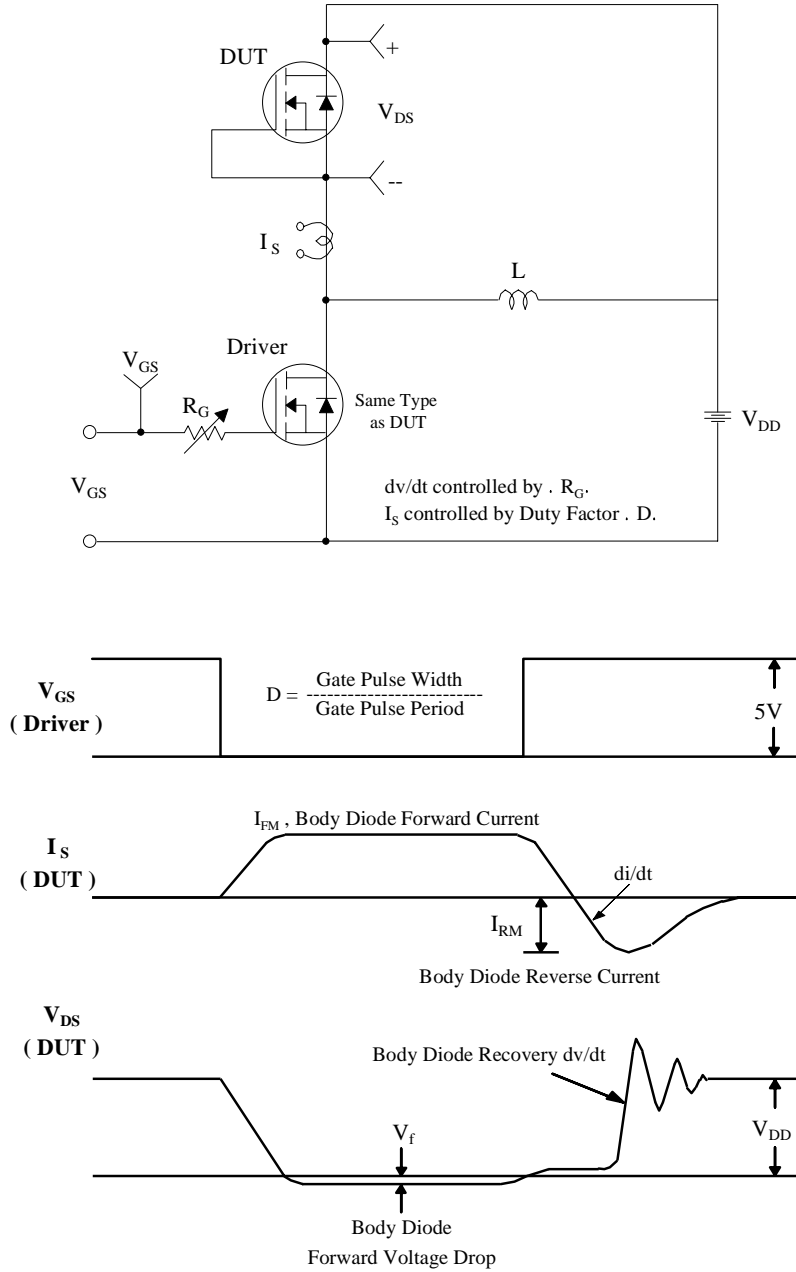


Fig 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms



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